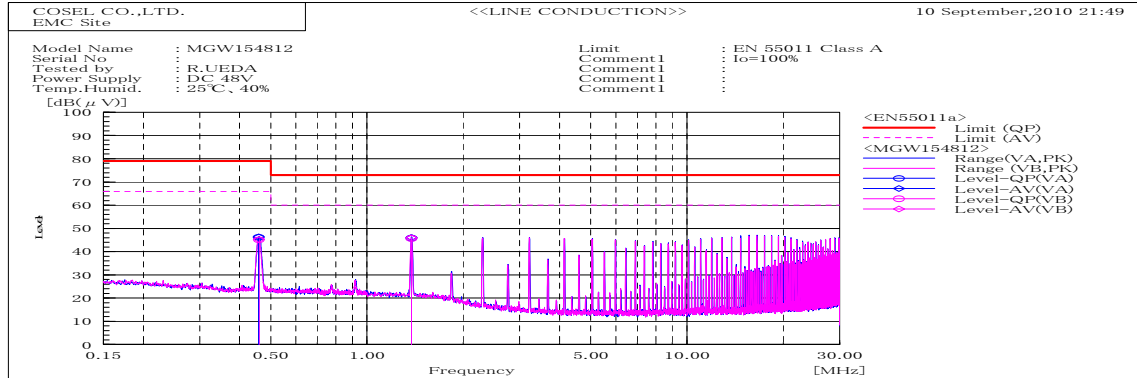
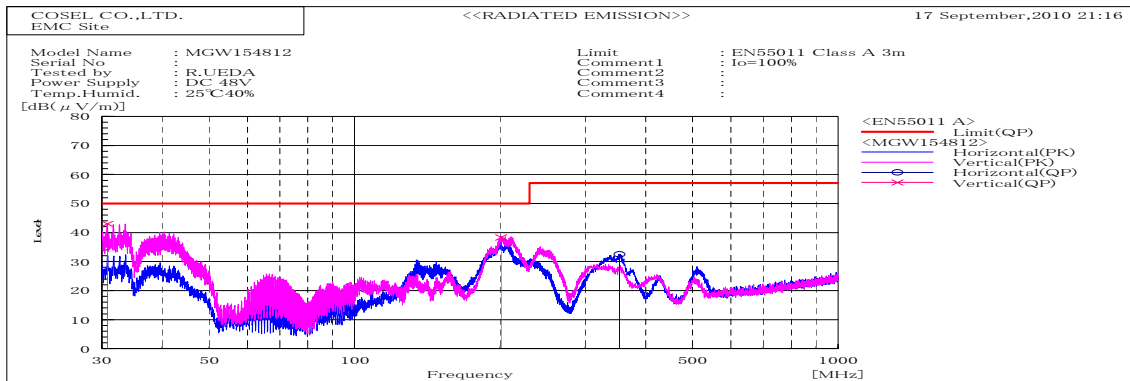


DATA SHEET		Date	21-Sep-10
Model	MGW154812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45893		VA	36.1	36.3	10.1	46.2	46.4	79	66	32.8	19.6	Pass	
0.45923		VB	35.1	35.2	10	45.1	45.2	79	66	33.9	20.8	Pass	
1.37692		VA	35.7	35.9	10.1	45.8	46	73	60	27.2	14	Pass	
1.37778		VB	35.6	35.8	10.1	45.7	45.9	73	60	27.3	14.1	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.802	V	Stable	56.8	-13.8		43	50	7	Pass	100	25	
200.807	V	Stable	60.3	-22		38.3	50	11.7	Pass	141	114	
352.871	H	Stable	48.7	-16.2		32.5	57	24.5	Pass	104	0	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



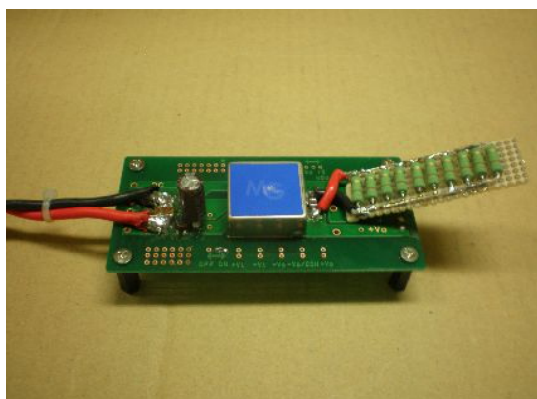


Conditions

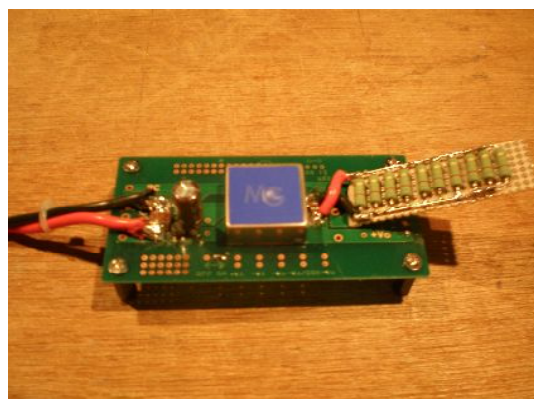
Test : EMI
Model Name : MGS1548□□/MGW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

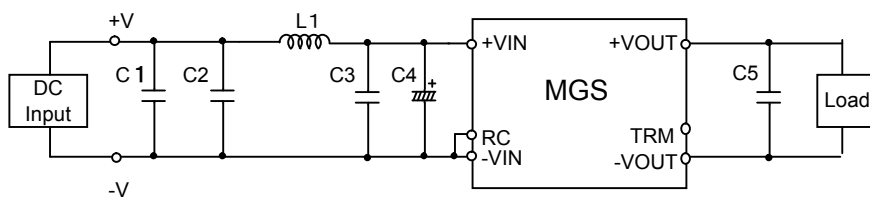


Fig.1 Testing circuitry 1

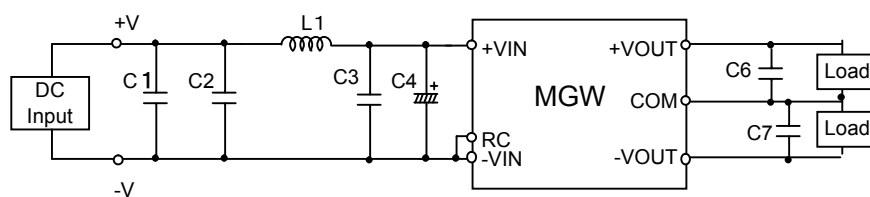


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)